

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of: )  
Shunpei YAMAZAKI et al. )  
Serial No. 09/466,828 ) Group Art Unit: 2818  
Filed: December 20, 1999 ) Examiner: R. Berry  
For: INSULATING FILM AND METHOD OF )  
PRODUCING SEMICONDUCTOR DEVICE )

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MAY 10 2002

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**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents and Trademarks  
Washington, D.C. 20231

Sir:

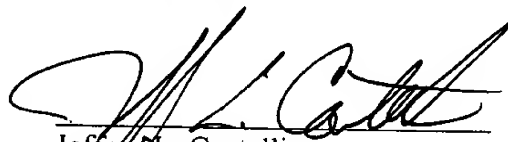
In accordance with the provisions of 37 C.F.R. 1.56 and 37 C.F.R. 1.97-1.99, it is requested that the references listed on the attached Form PTO-1449 be made of record in the above-identified application.

The references listed on the attached Form PTO-1449 were cited in counterpart Japanese applications on April 23, 2002. Copies of the references are submitted herewith in accordance with 37 C.F.R. 1.98(a).

JP 04-295826 teaches the use of quartz or a single crystal silicon as a target for forming a gate insulating film. U.S. Patent No. 5,585,949 is in the same family as JP 04-295826.

The Commissioner is hereby authorized to charge fees under 37 C.F.R. §§1.16, 1.17, 1.20(a), 1.20(b), 1.20(c), and 1.20(d) (except the Issue Fee) which may be required now or hereafter, or credit any overpayment to Deposit Account No. 19-2380 (740756-2077).

Respectfully submitted,

  
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Form PTO-1449  
(Rev. 8-83)U.S. Department of Commerce  
Patent and Trademark Office

Atty Docket 0756-2077

Serial No. 09/466,828

## INFORMATION DISCLOSURE STATEMENT

Applicants: Shunpei YAMAZAKI et al.

Filing Date: December 20, 1999

Group Art Unit: 2818

## U.S. PATENT DOCUMENTS

| Examiner Initial | Document Number | Date       | Name            | Class | Subclass | Filing Date (if appropriate) |
|------------------|-----------------|------------|-----------------|-------|----------|------------------------------|
|                  | 5,585,949       | 12/17/1996 | Yamazaki et al. |       |          |                              |

## FOREIGN PATENT DOCUMENTS

| Examiner Initial | Document Number | Date       | Country | Class | Subclass | Translation<br>Yes No |
|------------------|-----------------|------------|---------|-------|----------|-----------------------|
|                  | 04-295826       | 10/20/1992 | JP      |       |          | Eng Abst              |

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Examiner

Date Considered

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

05/10/2002